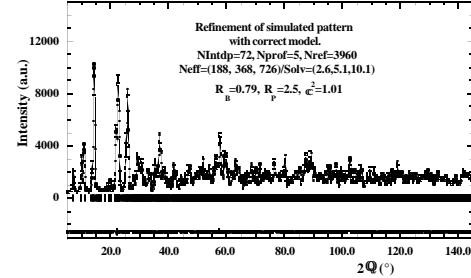
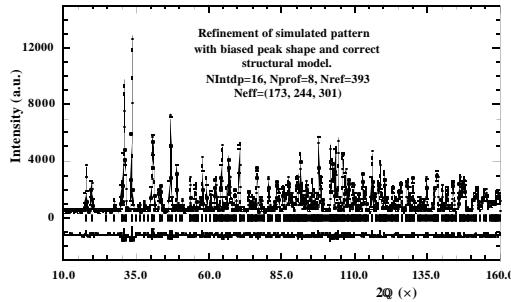


**Results of simulations:
Refinements of simulated powder
diffraction patterns using correct
and biased models**

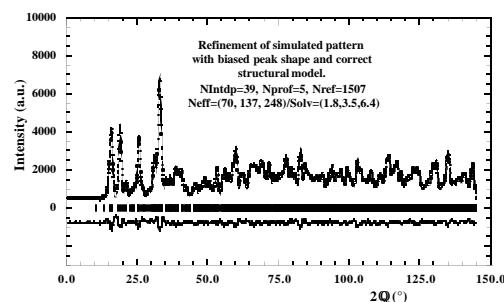
**RM (systematic errors): Correct structural and
peak shape model $N_i=72$ (Plot-pattern)**



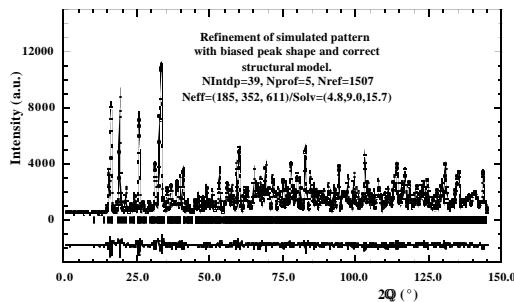
**RM (systematic errors): Correct structural
model, biased peak shape $N_i=16$ (Plot-pattern)**



**RM (systematic errors): Biased peak shape+
correct structural model $N_i=39$ + bad resolution**

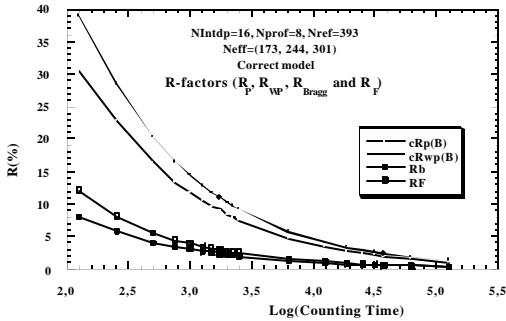


**RM (systematic errors): Biased peak shape+ correct
structural model $N_i=39$ + better resolution**

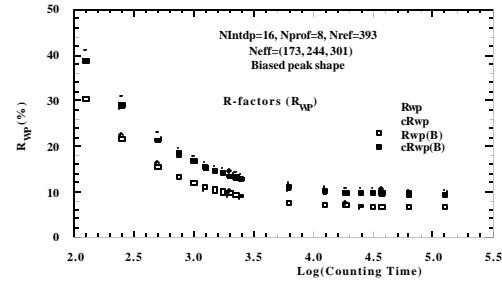


**Behaviour of Rietveld R-factors,
and other indicators, versus
counting statistics for perfect and
biased models**

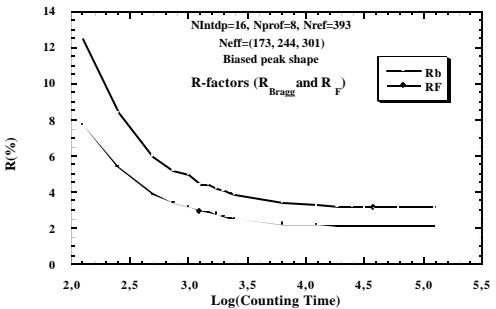
RM (systematic errors): Behaviour of R-factors versus counting time (correct model)



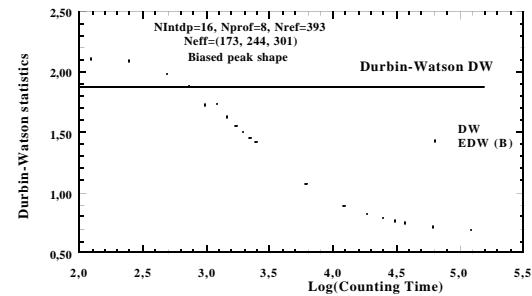
RM (systematic errors): Behaviour of R_{wp} factors versus counting time (biased peak shape)



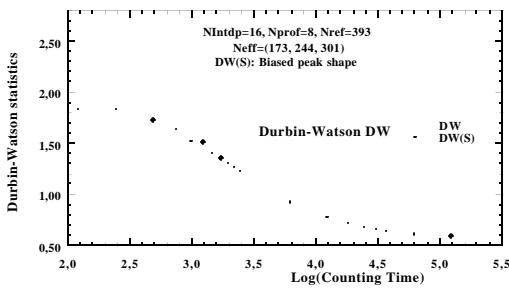
RM (systematic errors): Behaviour of R_{Bragg} and R_F factors versus counting time (biased peak shape)



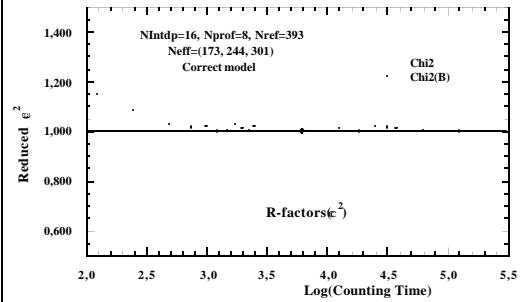
RM (systematic errors): Behaviour of DW indicators versus counting time (biased peak shape)



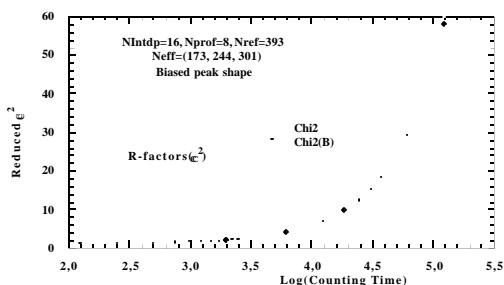
RM (systematic errors): Behaviour of DW indicator versus counting time (biased/unbiased peak shape)



RM (systematic errors): Behaviour of reduced Chi-square versus counting time (correct model)

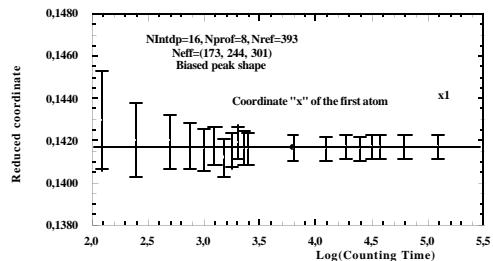


RM (systematic errors): Behaviour of reduced Chi-square versus counting time (biased peak shape)



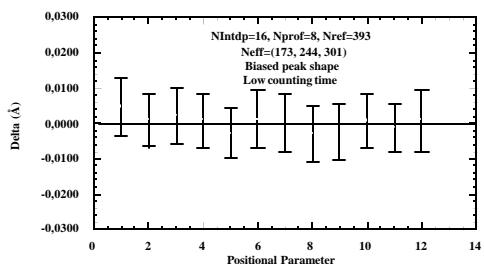
Behaviour of positional parameters (atom co-ordinates), versus counting statistics, resolution, ... for perfect and biased models

RM (systematic errors): Behaviour of positional parameters versus counting time (biased peak shape)

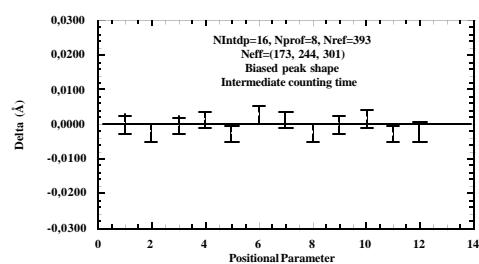


Atom co-ordinates versus counting statistics

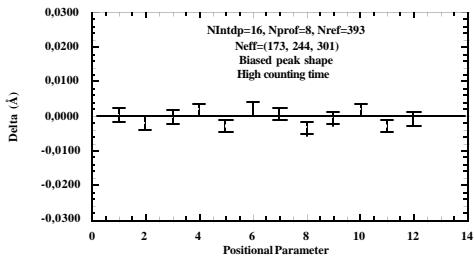
RM (systematic errors): Positional parameters $N_I=16$, Low counting time (biased peak shape)



RM (systematic errors): Positional parameters, $N_I=16$ Intermediate counting time (biased peak shape)

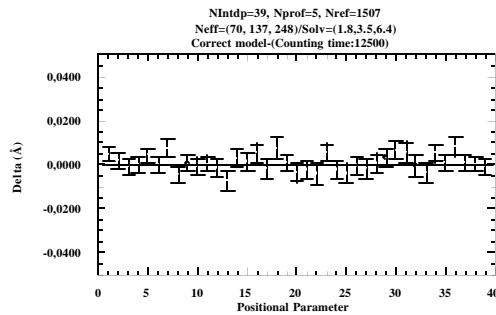


RM (systematic errors): Positional parameters, $N_I=16$
High counting time (biased peak shape)

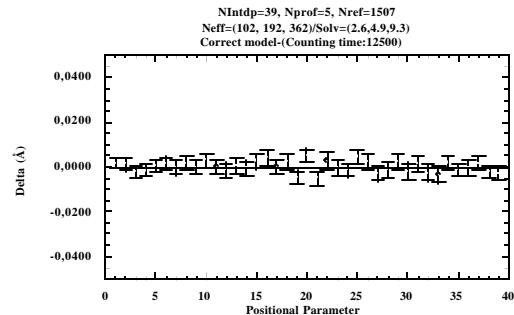


Atom co-ordinates versus
resolution (“solvability index”)
 $r=N_{\text{eff}}/N_I$

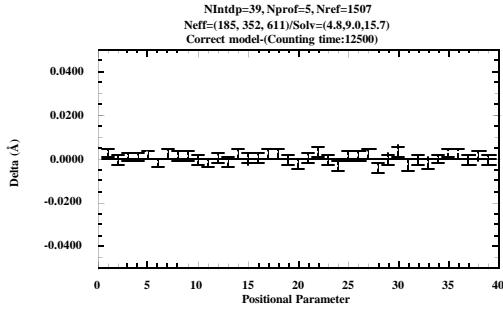
**RM (systematic errors): Positional parameters
 $N_I=39$, Counting Time: 12500 (correct model, $r=3.5$)**



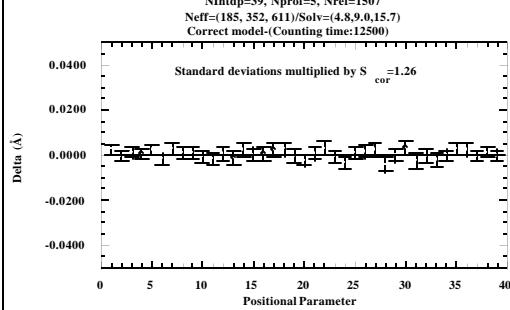
**RM (systematic errors): Positional parameters
 $N_I=39$, Counting Time: 12500 (correct model, $r=4.9$)**

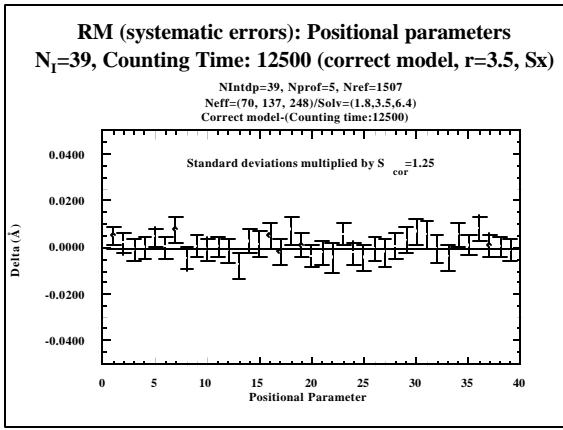


**RM (systematic errors): Positional parameters
 $N_I=39$, Counting Time: 12500 (correct model, $r=9$)**

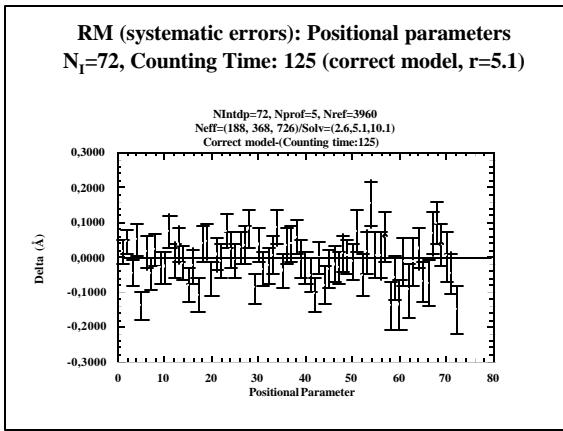


**RM (systematic errors): Positional parameters
 $N_I=39$, Counting Time: 12500 (correct model, $r=9$, Sx)**

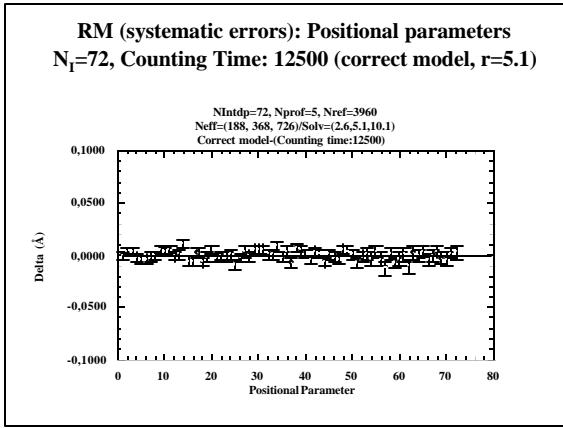
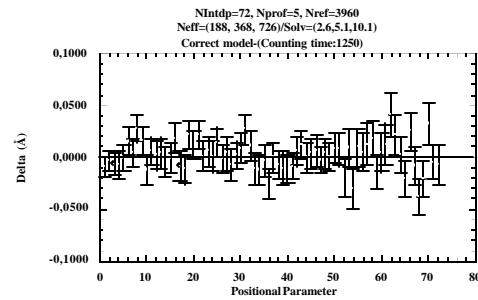




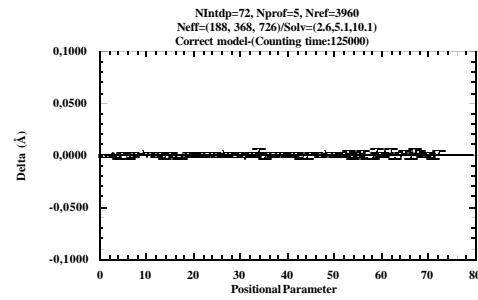
Atom co-ordinates versus
statistics (correct model, $N_I=72$)



RM (systematic errors): Positional parameters
 $N_I=72$, Counting Time: 1250 (correct model, $r=5.1$)



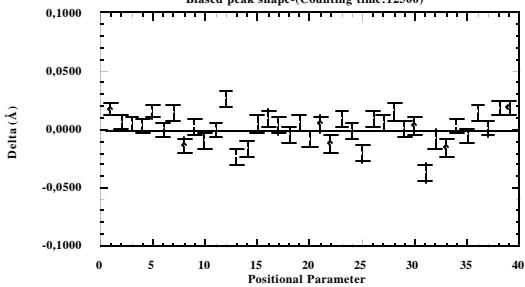
RM (systematic errors): Positional parameters
 $N_I=72$, Counting Time: 125000 (correct model, $r=5.1$)



**Atom co-ordinates versus
statistics**
 (biased peak shape, $N_I=39$)

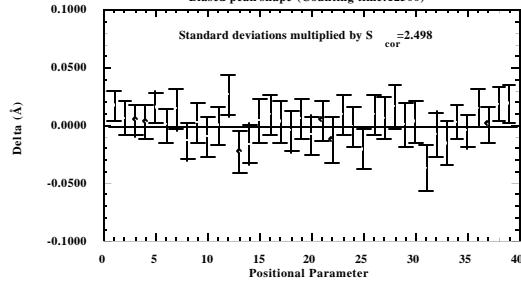
RM (systematic errors): Positional parameters
 $N_I=39$, Counting Time: 12500 (biased peak shape, $r=9$)

NIIntdp=39, Nprof=5, Nref=1507
 Neff=(185, 352, 611)/Solv=(4,8,9,0,15,7)
 Biased peak shape-(Counting time:12500)



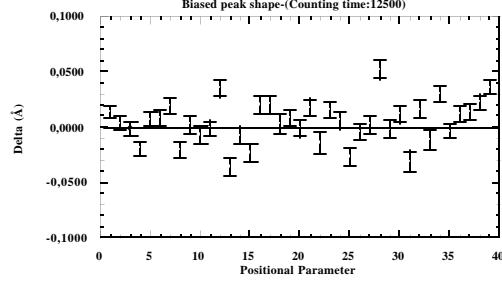
RM (systematic errors): Positional parameters
 $N_I=39$, Counting Time: 12500 (biased peak shape, $r=9$, Sx)

NIIntdp=39, Nprof=5, Nref=1507
 Neff=(185, 352, 611)/Solv=(4,8,9,0,15,7)
 Biased peak shape-(Counting time:12500)



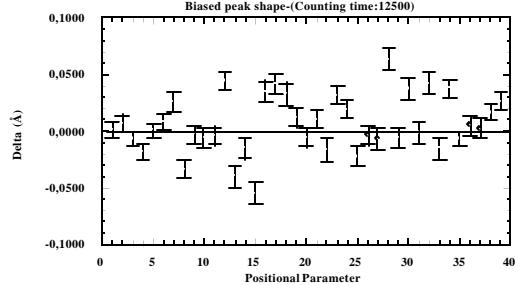
RM (systematic errors): Positional parameters
 $N_I=39$, Counting Time: 12500 (biased peak shape, $r=4.9$)

NIIntdp=39, Nprof=5, Nref=1507
 Neff=(102, 192, 362)/Solv=(2,6,4,9,9,3)
 Biased peak shape-(Counting time:12500)



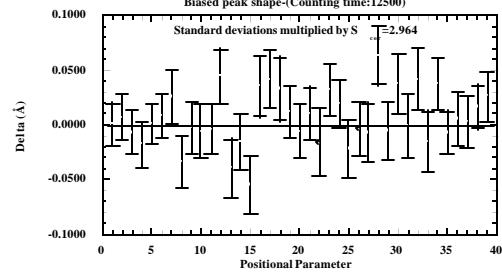
RM (systematic errors): Positional parameters
 $N_I=39$, Counting Time: 12500 (biased peak shape, $r=3.5$)

NIIntdp=39, Nprof=5, Nref=1507
 Neff=(70, 137, 248)/Solv=(1,8,3,5,6,4)
 Biased peak shape-(Counting time:12500)



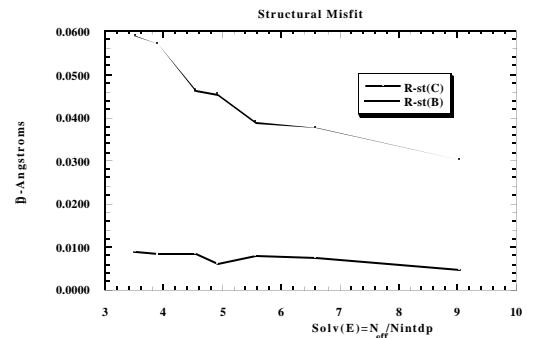
RM (systematic errors): Positional parameters
 $N_I=39$, Counting Time: 12500 (biased peak shape, $r=3.5$, Sx)

NIIntdp=39, Nprof=5, Nref=1507
 Neff=(70, 137, 248)/Solv=(1,8,3,5,6,4)
 Biased peak shape-(Counting time:12500)



Structural misfit versus resolution

RM (systematic errors): Structural misfit versus N_{eff}/N_I



RM (systematic errors): Structural misfit versus N_{eff}/N_I

